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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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OF

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Complete if Known

Application Number	10/710,012
Filing Date	June 11, 2004
Applicant(s)	Chien-Chao Huang, et al.
Art Unit	2811-2812
Examiner Name	Tsao
Attorney Docket Number	2001.1531 / 24061.439

U. S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document
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OTHER PRIOR ART

Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume, issue number(s), publisher, city, country where published
SH	AH	GLUCK, M., et al., "CoSi ₂ and TiSi ₂ for Si/SiGe Heterodevices", Elsevier Science S.A., Thin Solid Films 270, 1995, pages 549-554.
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	AK	XIANG, QI, et al., "Strained Silicon NMOS with Nickel-Silicide Metal Gate", 2003 Symposium on VLSI Technology Digest of Technical Papers, 4-89114-035-6/03, 2 pages.
	AL	YEO, YEE-CHIA, et al, "Enhanced Performance in Sub-100 nm CMOSFETs Using Strained Epitaxial Silicon-Germanium", IEDM, pages 753-756.

Examiner Signature	<i>Shaneta Lane</i>	Date Considered	9/18/05
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